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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	200
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	70
Number of Gates	1500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1415a-1pl84m

Product Plan

Device/Package	Speed Grade ¹				Application ¹			
	Std.	–1	–2	–3	C	I	M	B
A1415A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	✓	–
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	✓	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	✓	–
100-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	–	–
A14V15A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
A1425A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓		
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	–	–
132-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
133-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	D	D
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
A14V25A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A1440A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
175-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–

Notes:

- Applications:
C = Commercial
I = Industrial
M = Military
- Commercial only

Availability:
✓ = Available
P = Planned
– = Not planned
D = Discontinued

Speed Grade:
–1 = Approx. 15% faster than Std.
–2 = Approx. 25% faster than Std.
–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

2 – Detailed Specifications

This section of the datasheet is meant to familiarize the user with the architecture of the ACT 3 family of FPGA devices. A generic description of the family will be presented first, followed by a detailed description of the logic blocks, the routing structure, the antifuses, and the special function circuits. The on-chip circuitry required to program the devices is not covered.

Topology

The ACT 3 family architecture is composed of six key elements: Logic modules, I/O modules, I/O Pad Drivers, Routing Tracks, Clock Networks, and Programming and Test Circuits. The basic structure is similar for all devices in the family, differing only in the number of rows, columns, and I/Os. The array itself consists of alternating rows of modules and channels. The logic modules and channels are in the center of the array; the I/O modules are located along the array periphery. A simplified floor plan is depicted in Figure 2-1.

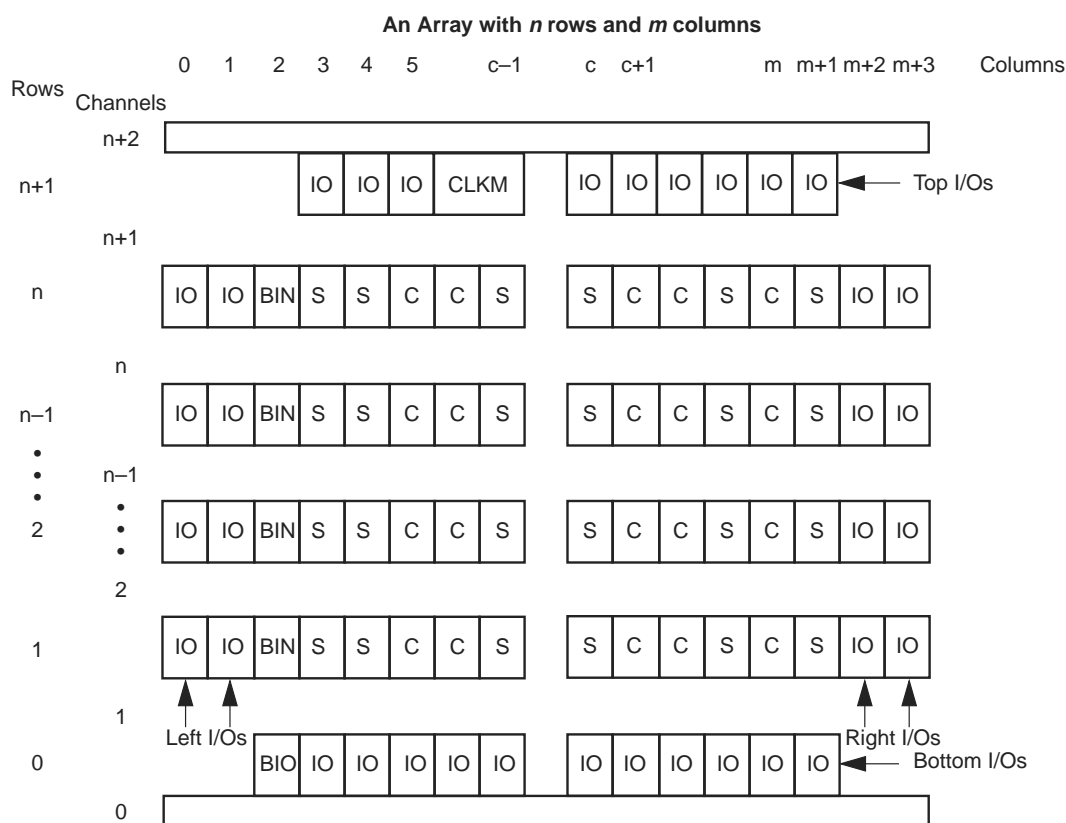


Figure 2-1 • Generalized Floor Plan of ACT 3 Device

The S-module contains a full implementation of the C-module plus a clearable sequential element that can either implement a latch or flip-flop function. The S-module can therefore implement any function implemented by the C-module. This allows complex combinatorial-sequential functions to be implemented with no delay penalty. The Designer Series Development System will automatically combine any C-module macro driving an S-module macro into the S-module, thereby freeing up a logic module and eliminating a module delay.

The clear input CLR is accessible from the routing channel. In addition, the clock input may be connected to one of three clock networks: CLKA, CLKB, or HCLK. The C-module and S-module functional descriptions are shown in Figure 2-2 and Figure 2-3 on page 2-2. The clock selection is determined by a multiplexer select at the clock input to the S-module.

I/Os

I/O Modules

I/O modules provide an interface between the array and the I/O Pad Drivers. I/O modules are located in the array and access the routing channels in a similar fashion to logic modules. The I/O module schematic is shown in Figure 4. The signals DataIn and DataOut connect to the I/O pad driver.

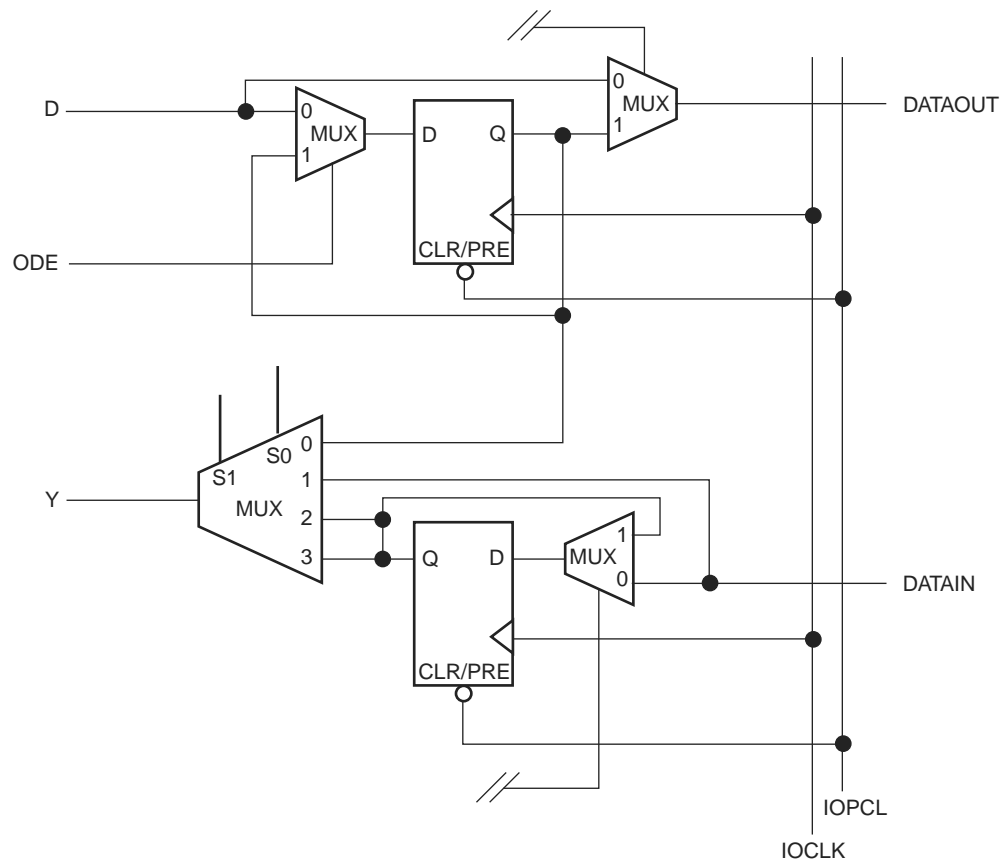


Figure 2-4 • Functional Diagram for I/O Module

Each I/O module contains two D-type flip-flops. Each flip-flop is connected to the dedicated I/O clock (IOCLK). Each flip-flop can be bypassed by nonsequential I/Os. In addition, each flip-flop contains a data enable input that can be accessed from the routing channels (ODE and IDE). The asynchronous preset/clear input is driven by the dedicated preset/clear network (IOPCL). Either preset or clear can be selected individually on an I/O module by I/O module basis.

5 V Operating Conditions

Table 2-2 • Absolute Maximum Ratings¹, Free Air Temperature Range

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current ²	±20	mA
T _{STG}	Storage temperature	–65 to +150	°C

Notes:

- Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.
- Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.

Table 2-3 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature range*	0 to +70	–40 to +85	–55 to +125	°C
5 V power supply tolerance	±5	±10	±10	%VCC

Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.

Table 2-4 • Electrical Specifications

Symbol	Parameter	Test Condition	Commercial		Industrial		Military		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
VOH ^{1,2}	High level output	IOH = –4 mA (CMOS)	–	–	3.7	–	3.7	–	V
		IOH = –6 mA (CMOS)	3.84						V
		IOH = –10 mA (TTL) ³	2.40						V
VOL ^{1,2}	Low level output	IOL = +6 mA (CMOS)		0.33		0.4		0.4	V
		IOL = +12 mA (TTL) ³		0.50					
VIH	High level input	TTL inputs	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIL	Low level input	TTL inputs	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
IIN	Input leakage	VI = VCC or GND	–10	+10	–10	+10	–10	+10	μA
IOZ	3-state output leakage	VO = VCC or GND	–10	+10	–10	+10	–10	+10	μA
C _{IO}	I/O capacitance ^{3,4}			10		10		10	pF
ICC(S)	Standby VCC supply current (typical = 0.7 mA)			2		10		20	mA
ICC(D)	Dynamic VCC supply current. See the Power Dissipation section.								

Notes:

- Microsemi devices can drive and receive either CMOS or TTL signal levels. No assignment of I/Os as TTL or CMOS is required.
- Tested one output at a time, VCC = minimum.
- Not tested; for information only.
- V_{OUT} = 0 V, f = 1 MHz
- Typical standby current = 0.7 mA. All outputs unloaded. All inputs = VCC or GND.

Power Dissipation

$$P = [ICC_{\text{standby}} + I_{\text{active}}] * VCC * IOL * VOL * N + IOH * (VCC - VOH) * M$$

EQ 3

where:

ICC standby is the current flowing when no inputs or outputs are changing

Iactive is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source current.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M equals the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the design and on the system I/O. The power can be divided into two components: static and active.

Static Power Component

Microsemi FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated in Table 2-9 for commercial, worst case conditions.

Table 2-9 • Standby Power Calculation

ICC	VCC	Power
2 mA	5.25 V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

Active Power Component

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces and load device inputs.

An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by EQ 4.

$$\text{Power } (\mu\text{W}) = C_{\text{EQ}} * VCC^2 * F$$

EQ 4

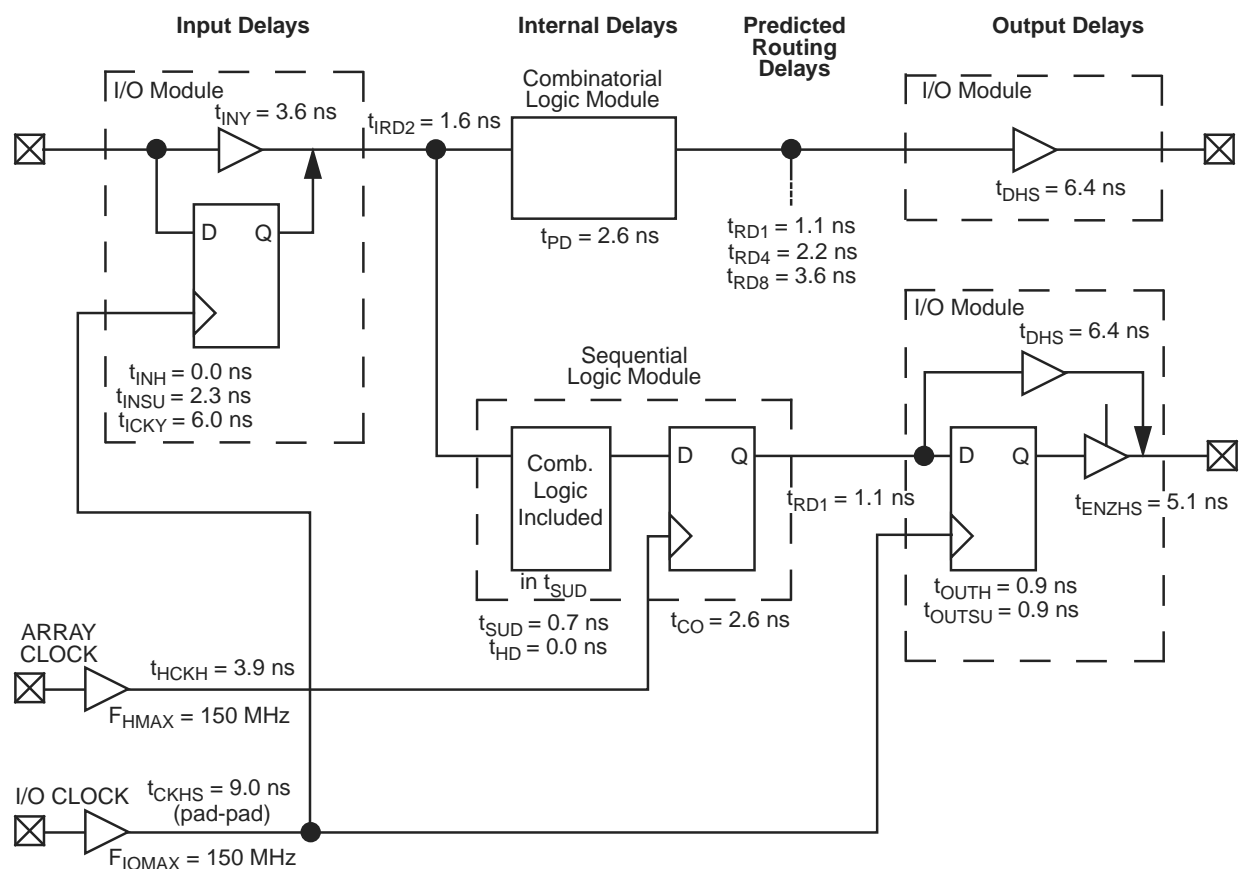
Where:

C_{EQ} is the equivalent capacitance expressed in pF.

VCC is the power supply in volts.

F is the switching frequency in MHz.

ACT 3 Timing Model



Note: Values shown for A1425A -1 speed grade device.

Figure 2-10 • Timing Model

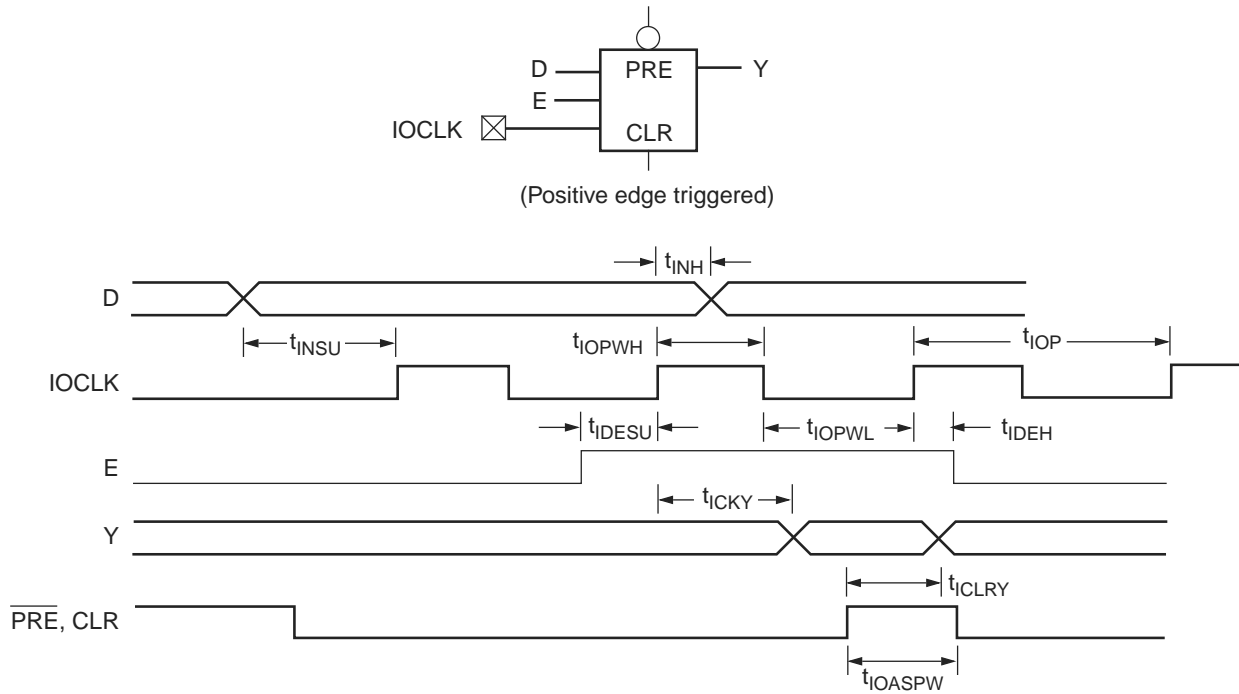


Figure 2-16 • I/O Module: Sequential Input Timing Characteristics

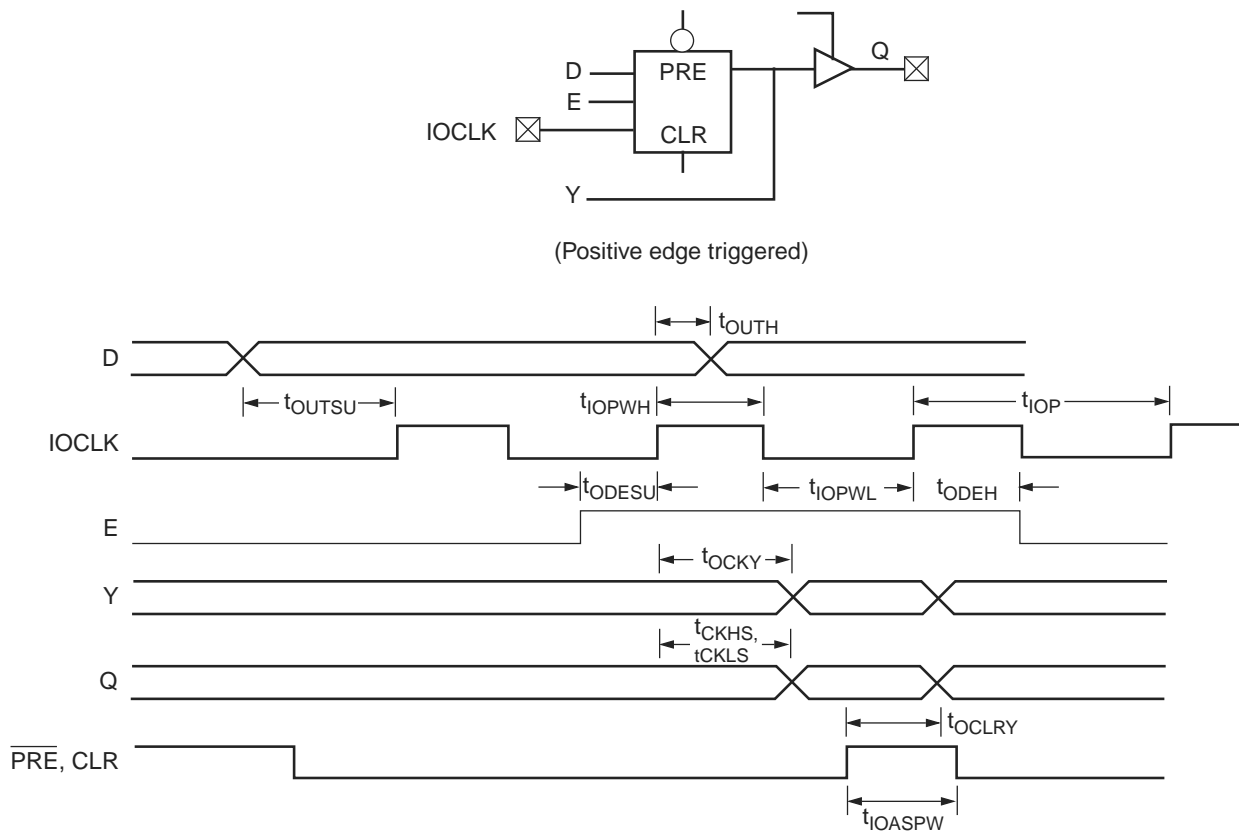


Figure 2-17 • I/O Module: Sequential Output Timing Characteristics

A1415A, A14V15A Timing Characteristics (continued)

Table 2-21 • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

Dedicated (hardwired) I/O Clock Network		–3 Speed		–2 Speed		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{IOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t _{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t _{IOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t _{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t _{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t _{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t _{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f _{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
t _{IOHCKSW}	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t _{IORCKSW}	I/O Clock to R-Clock Skew (FO = 64)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
t _{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 50% maximum)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns

Notes:

- Delays based on 35 pF loading.
- The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

A1425A, A14V25A Timing Characteristics (continued)

Table 2-23 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module Input Propagation Delays		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t _{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays²												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t _{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input F-F Data Setup	1.8		2.0		2.3		2.7		3.0		ns
t _{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t _{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t _{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t _{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f _{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes: *

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1440A, A14V40A Timing Characteristics

Table 2-26 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		–3 Speed ³		–2 Speed ³		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _A	Flip-Flop Clock Input Period	4.0		5.0		6.8		8.0		10.0		ns
f _{MAX}	Flip-Flop Clock Frequency		250		200		150		125		100	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.
2. For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1440A, A14V40A Timing Characteristics (continued)

Table 2-29 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

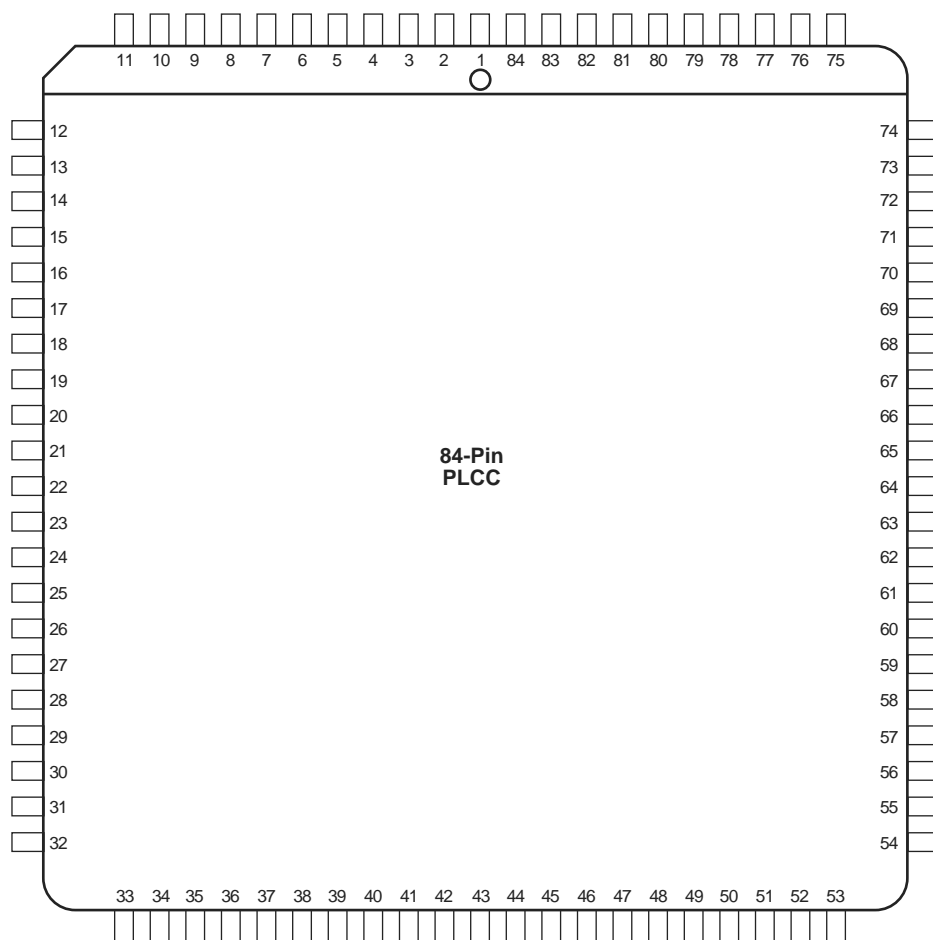
Dedicated (hardwired) I/O Clock Network		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ILOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t _{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t _{ILOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t _{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t _{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t _{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t _{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f _{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
t _{IOHCKSW}	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t _{IORCKSW}	I/O Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	
t _{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

Notes:

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Delays based on 35 pF loading.

3 – Package Pin Assignments

PL84

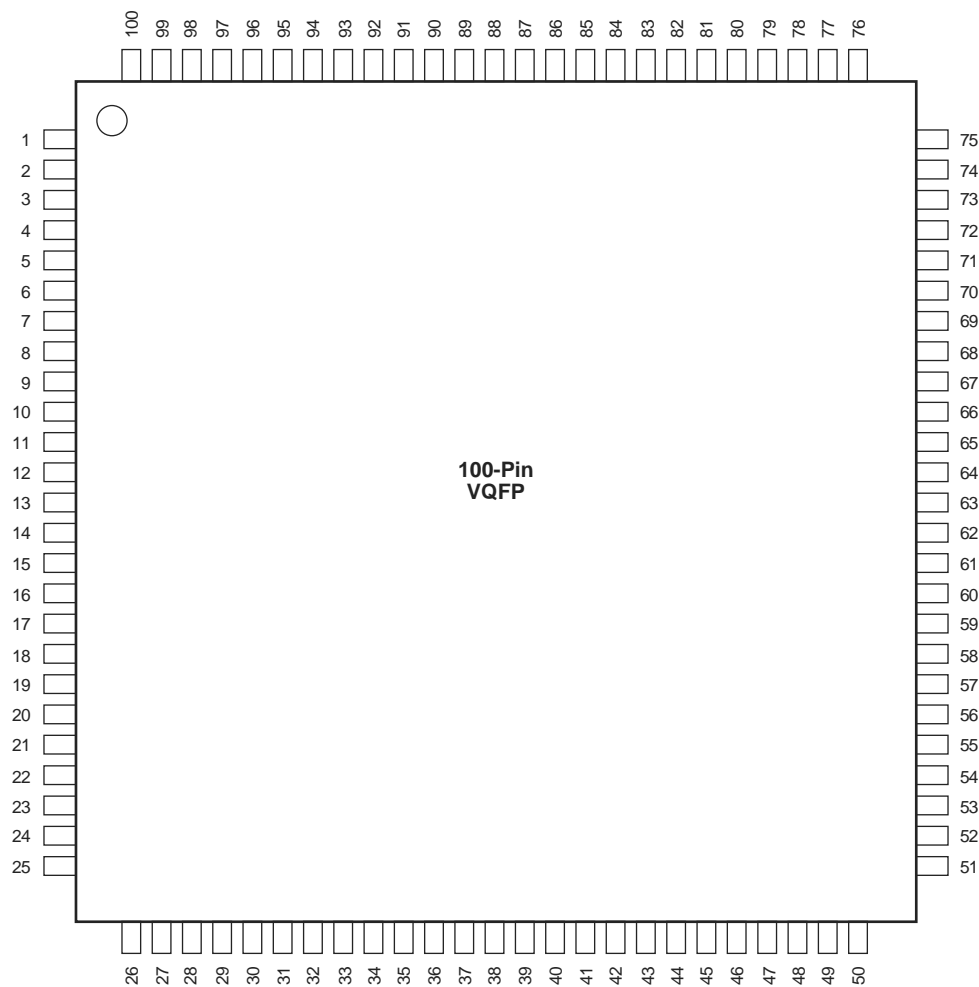


Note: This is the top view of the package.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>.

VQ100



Note: This is the top view.

Note

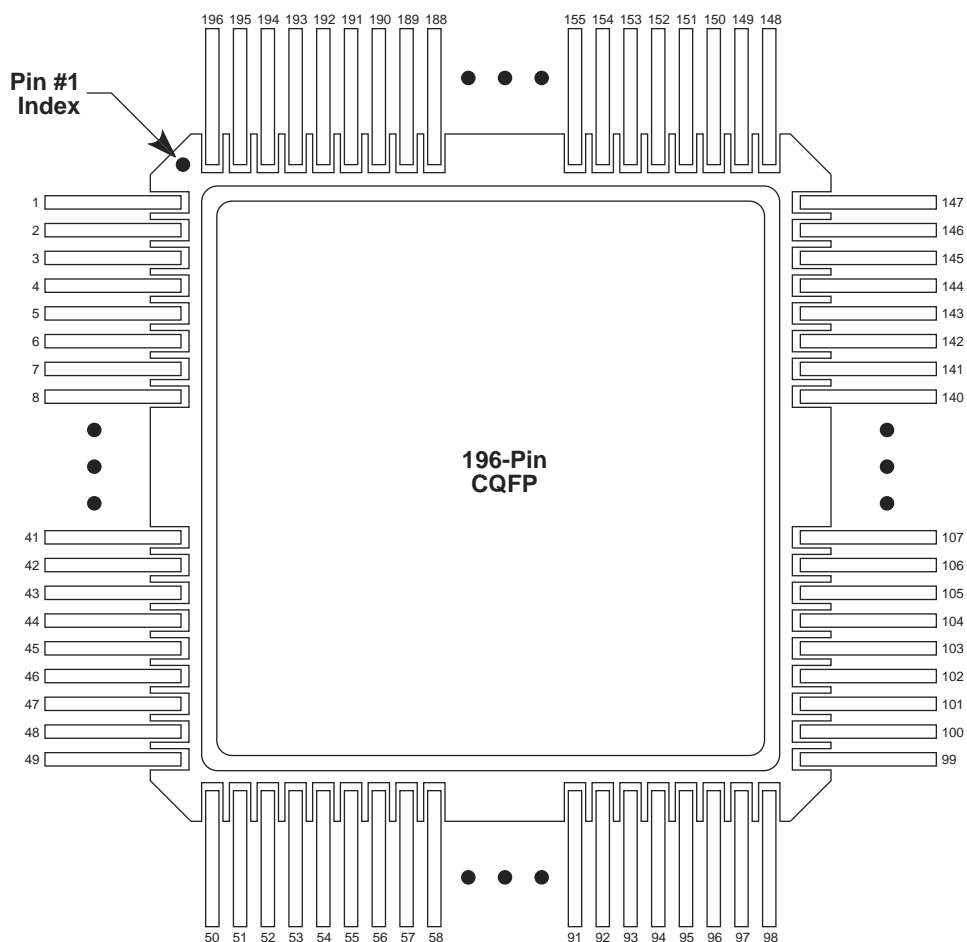
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

CQ132		CQ132	
Pin Number	A1425 Function	Pin Number	A1425 Function
1	NC	67	NC
2	GND	74	GND
3	SDI, I/O	75	VCC
9	MODE	78	VCC
10	GND	89	VCC
11	VCC	90	GND
22	VCC	91	VCC
26	GND	92	GND
27	VCC	98	IOCLK, I/O
34	NC	99	NC
36	GND	100	NC
42	GND	101	GND
43	VCC	106	GND
48	PRB, I/O	107	VCC
50	HCLK, I/O	116	CLKA, I/O
58	GND	117	CLKB, I/O
59	VCC	118	PRA, I/O
63	SDO	122	GND
64	IOPCL, I/O	123	VCC
65	GND	131	DCLK, I/O
66	NC	132	NC

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ196

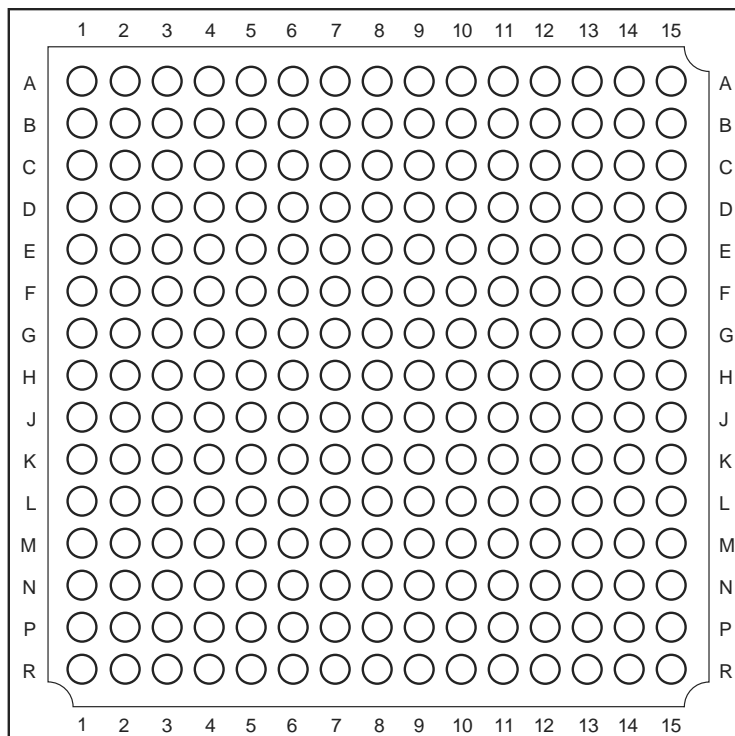


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

BG225

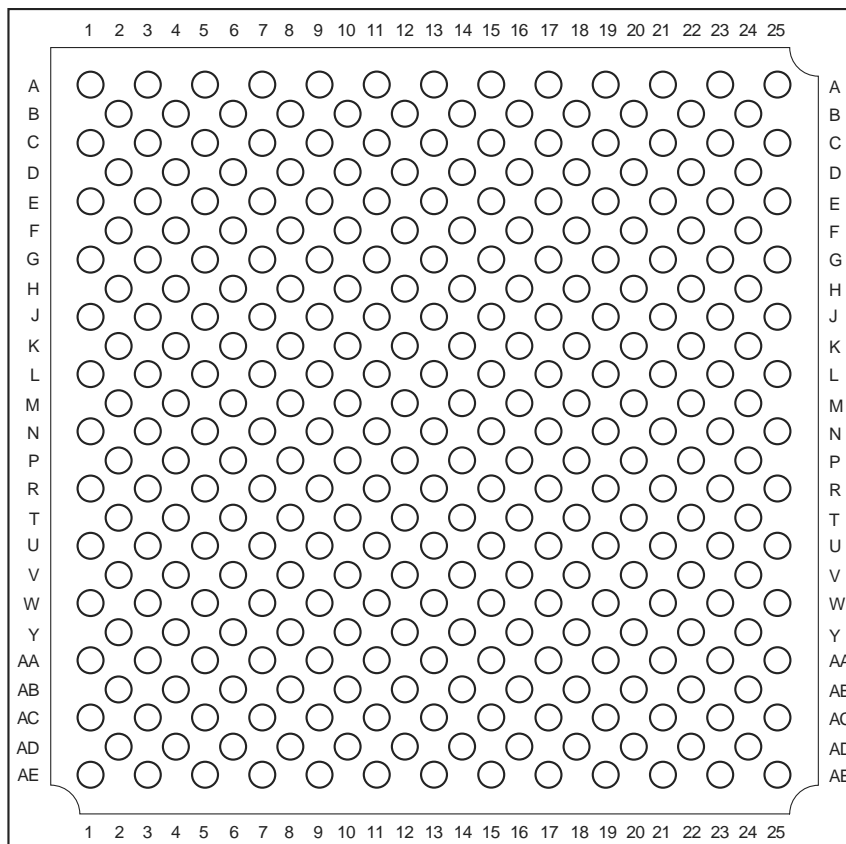


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

BG313

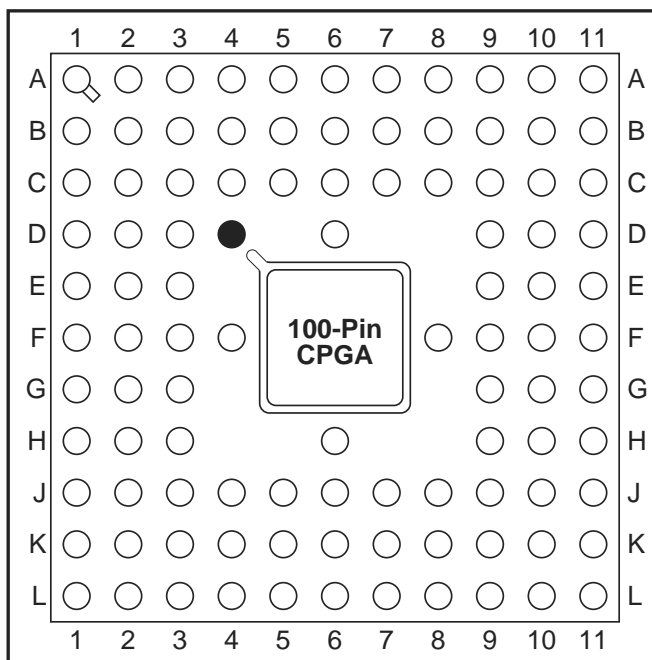


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG100



● Orientation Pin

Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG175	
A1440 Function	Location
CLKA or I/O	C9
CLKB or I/O	A9
DCLK or I/O	D5
GND	D4, D8, D11, D12, E4, E14, H4, H12, L4, L12, M4, M8, M12
HCLK or I/O	R8
IOCLK or I/O	E12
IOPCL or I/O	P13
MODE	F3
NC	A1, A2, A15, B2, B3, P2, P14, R1, R2, R14, R15
PRA or I/O	B8
PRB or I/O	R7
SDI or I/O	D3
SDO	N12
VCC	C3, C8, C13, E15, H3, H13, L1, L14, N3, N8, N13

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG175 package has been discontinued.

PG207	
A1460 Function	Location
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.